

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/615,021	CHANG, WON-KIL	
			Examiner	Art Unit	Page 1 of 1
			Shih-wen Hsieh	2861	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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